

Application/Control No.	Applicant(s)/Patent under Reexamination
10/530,271	YOSHIHARA ET AL.
Examiner	Art Unit
Matthew C. Landau	2815

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SEARCHED					
Class	Subclass	Date	Examiner		
257	295	11/17/07	7		
365 360	158, 171, 173, 209 324.2				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

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